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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	F ² MC-16FX
Core Size	16-Bit
Speed	32MHz
Connectivity	CANbus, I ² C, LINbus, SCI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	52
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 21x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb96f622rbpmc-gse2

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Pin name	Feature	Description
WOT	RTC	Real Time clock output pin
X0	Clock	Oscillator input pin
X0A	Clock	Subclock Oscillator input pin
X1	Clock	Oscillator output pin
X1A	Clock	Subclock Oscillator output pin
ZINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin

5. Pin Circuit Type

Pin no.	I/O circuit type*	Pin name
1	Supply	AVss
2	G	AVRH
3	K	P06_2 / AN2
4	K	P06_3 / AN3 / PPG3
5	K	P06_4 / AN4 / PPG4
6	K	P06_5 / AN5
7	K	P06_6 / AN6 / PPG6
8	K	P06_7 / AN7 / PPG7
9	I	P05_0 / AN8 / SIN2 / INT3_R1
10	K	P05_1 / AN9 / SOT2
11	I	P05_2 / AN10 / SCK2
12	K	P05_3 / AN11 / TIN3 / WOT
13	K	P05_4 / AN12 / TOT3 / INT2_R
14	K	P05_5 / AN13 / INT0_R / NMI_R
15	K	P05_6 / AN14 / INT4_R
16	H	P04_2 / IN6 / INT9_R / TTG6 / TTG14
17	H	P04_3 / IN7 / TTG7 / TTG15
18	Supply	Vss
19	B	P04_0 / X0A
20	B	P04_1 / X1A
21	C	MD
22	H	P17_0
23	O	DEBUG I/F
24	M	P00_0 / INT8 / SCK7_R / PPG0_B
25	H	P00_1 / INT9 / SOT7_R / PPG1_B
26	M	P00_2 / INT10 / SIN7_R
27	M	P00_3 / INT11 / SCK8_R / PPG3_B
28	H	P00_4 / INT12 / SOT8_R / PPG12_B
29	M	P00_5 / INT13 / SIN8_R / PPG14_B
30	H	P00_6 / INT14
31	H	P00_7 / INT15
32	H	P01_0 / TIN1 / CKOT1 / OUT0_R

8. RAMSTART Addresses

Devices	Bank 0 RAM size	RAMSTART0
MB96F622	4KB	00:7200H
MB96F623	10KB	00:5A00H
MB96F625		

9. User ROM Memory Map For Flash Devices

		MB96F622	MB96F623	MB96F625	
CPU mode address	Flash memory mode address	Flash size 32.5KB + 32KB	Flash size 64.5KB + 32KB	Flash size 128.5KB + 32KB	
FF:FFFF _H	3F:FFFF _H	SA39 - 32KB		SA39 - 64KB	
FF:8000 _H	3F:8000 _H				
FF:7FFF _H	3F:7FFF _H				
FF:0000 _H	3F:0000 _H				
FE:FFFF _H	3E:FFFF _H				
FE:0000 _H	3E:0000 _H			SA38 - 64KB	
FD:FFFF _H					
DF:A000 _H		Reserved	Reserved	Reserved	
DF:9FFF _H	1F:9FFF _H	SA4 - 8KB		SA4 - 8KB	
DF:8000 _H	1F:8000 _H				
DF:7FFF _H	1F:7FFF _H	SA3 - 8KB		SA3 - 8KB	
DF:6000 _H	1F:6000 _H				
DF:5FFF _H	1F:5FFF _H	SA2 - 8KB		SA2 - 8KB	
DF:4000 _H	1F:4000 _H				
DF:3FFF _H	1F:3FFF _H	SA1 - 8KB		SA1 - 8KB	
DF:2000 _H	1F:2000 _H				
DF:1FFF _H	1F:1FFF _H	SAS - 512B*		SAS - 512B*	
DF:0000 _H	1F:0000 _H				
DE:FFFF _H		Reserved	Reserved	Reserved	
DE:0000 _H					

Bank A of Flash A

Bank B of Flash A

Bank A of Flash A

*: Physical address area of SAS-512B is from DF:0000_H to DF:01FF_H.

Others (from DF:0200_H to DF:1FFF_H) is mirror area of SAS-512B.

Sector SAS contains the ROM configuration block RCBA at CPU address DF:0000_H -DF:01FF_H.

SAS can not be used for E²PROM emulation.

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
123	210H	-	-	123	Reserved
124	20CH	-	-	124	Reserved
125	208H	-	-	125	Reserved
126	204H	-	-	126	Reserved
127	200H	-	-	127	Reserved
128	1FC _H	-	-	128	Reserved
129	1F8H	-	-	129	Reserved
130	1F4H	-	-	130	Reserved
131	1F0H	-	-	131	Reserved
132	1EC _H	-	-	132	Reserved
133	1E8H	FLASHA	Yes	133	Flash memory A interrupt
134	1E4H	-	-	134	Reserved
135	1E0H	-	-	135	Reserved
136	1DC _H	-	-	136	Reserved
137	1D8H	QPRC0	Yes	137	Quad Position/Revolution counter 0
138	1D4H	QPRC1	Yes	138	Quad Position/Revolution counter 1
139	1D0H	ADCRC0	No	139	A/D Converter 0 - Range Comparator
140	1CC _H	-	-	140	Reserved
141	1C8H	-	-	141	Reserved
142	1C4H	-	-	142	Reserved
143	1C0H	-	-	143	Reserved

12. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

12.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

■ Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

■ Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

■ Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

1. Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

2. Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device. Therefore, avoid this type of connection.

3. Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

■ Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
2. Be sure that abnormal current flows do not occur during the power-on sequence.

■ Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

■ Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

■ Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

1. Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.
2. Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
3. Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 MΩ).
Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.
4. Ground all fixtures and instruments, or protect with anti-static measures.
5. Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.

12.3 Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

1. Humidity

Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

2. Discharge of Static Electricity

When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.

3. Corrosive Gases, Dust, or Oil

Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

4. Radiation, Including Cosmic Radiation

Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

5. Smoke, Flame

CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases.

Customers considering the use of Cypress products in other special environmental conditions should consult with sales representatives.

13. Handling Devices

Special care is required for the following when handling the device:

- Latch-up prevention
- Unused pins handling
- External clock usage
- Notes on PLL clock mode operation
- Power supply pins (V_{cc}/V_{ss})
- Crystal oscillator and ceramic resonator circuit
- Turn on sequence of power supply to A/D converter and analog inputs
- Pin handling when not using the A/D converter
- Notes on Power-on
- Stabilization of power supply voltage
- Serial communication
- Mode Pin (MD)

13.1 Latch-up prevention

CMOS IC chips may suffer latch-up under the following conditions:

- A voltage higher than V_{cc} or lower than V_{ss} is applied to an input or output pin.
- A voltage higher than the rated voltage is applied between V_{cc} pins and V_{ss} pins.
- The AV_{cc} power supply is applied before the V_{cc} voltage.

Latch-up may increase the power supply current dramatically, causing thermal damages to the device.

For the same reason, extra care is required to not let the analog power-supply voltage (AV_{cc} , $AVRH$) exceed the digital power-supply voltage.

13.2 Unused pins handling

Unused input pins can be left open when the input is disabled (corresponding bit of Port Input Enable register PIER = 0).

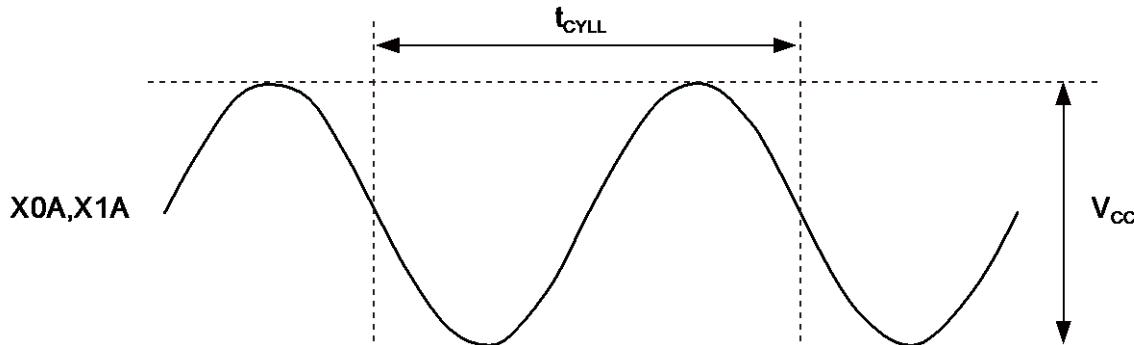
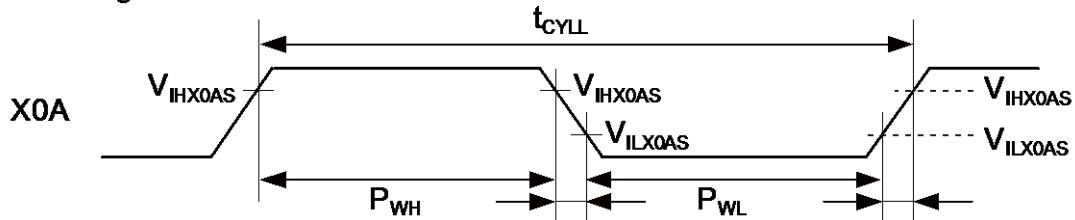
Leaving unused input pins open when the input is enabled may result in misbehavior and possible permanent damage of the device. To prevent latch-up, they must therefore be pulled up or pulled down through resistors which should be more than $2k\Omega$.

Unused bidirectional pins can be set either to the output state and be then left open, or to the input state with either input disabled or external pull-up/pull-down resistor as described above.

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks	
				Min	Typ	Max			
Power supply current in Timer modes ^{*2}	I _{CCTPLL}	V _{CC}	PLL Timer mode with CLKPLL = 32MHz (CLKRC and CLKSC stopped)	-	1800	2245	µA	T _A = +25°C	
				-	-	3165	µA	T _A = +105°C	
				-	-	3975	µA	T _A = +125°C	
	I _{CCTMAIN}		Main Timer mode with CLKMC = 4MHz, SMCR:LPMSS = 0 (CLKPLL, CLKRC and CLKSC stopped)	-	285	325	µA	T _A = +25°C	
				-	-	1085	µA	T _A = +105°C	
				-	-	1930	µA	T _A = +125°C	
	I _{CCTRCH}		RC Timer mode with CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKPLL, CLKMC and CLKSC stopped)	-	160	210	µA	T _A = +25°C	
				-	-	1025	µA	T _A = +105°C	
				-	-	1840	µA	T _A = +125°C	
	I _{CCTRCL}		RC Timer mode with CLKRC = 100kHz (CLKPLL, CLKMC and CLKSC stopped)	-	35	75	µA	T _A = +25°C	
				-	-	855	µA	T _A = +105°C	
				-	-	1640	µA	T _A = +125°C	
	I _{CCTSUB}		Sub Timer mode with CLKSC = 32kHz (CLKMC, CLKPLL and CLKRC stopped)	-	25	65	µA	T _A = +25°C	
				-	-	830	µA	T _A = +105°C	
				-	-	1620	µA	T _A = +125°C	

14.4.2 Sub Clock Input Characteristics
 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^\circ C \text{ to } +125^\circ C)$

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Input frequency	f_{CL}	X0A, X1A	-	-	32.768	-	kHz	When using an oscillation circuit
			-	-	-	100	kHz	When using an opposite phase external clock
		X0A	-	-	-	50	kHz	When using a single phase external clock
Input clock cycle	t_{CYLL}	-	-	10	-	-	μs	
Input clock pulse width	-	-	$P_{WH}/t_{CYLL}, P_{WL}/t_{CYLL}$	30	-	70	%	

When using the crystal oscillator

When using the external clock


14.4.3 Built-in RC Oscillation Characteristics
 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^\circ C \text{ to } +125^\circ C)$

Parameter	Symbol	Value			Unit	Remarks
		Min	Typ	Max		
Clock frequency	f_{RC}	50	100	200	kHz	When using slow frequency of RC oscillator
		1	2	4	MHz	When using fast frequency of RC oscillator
RC clock stabilization time	t_{RCSTAB}	80	160	320	μs	When using slow frequency of RC oscillator (16 RC clock cycles)
		64	128	256	μs	When using fast frequency of RC oscillator (256 RC clock cycles)

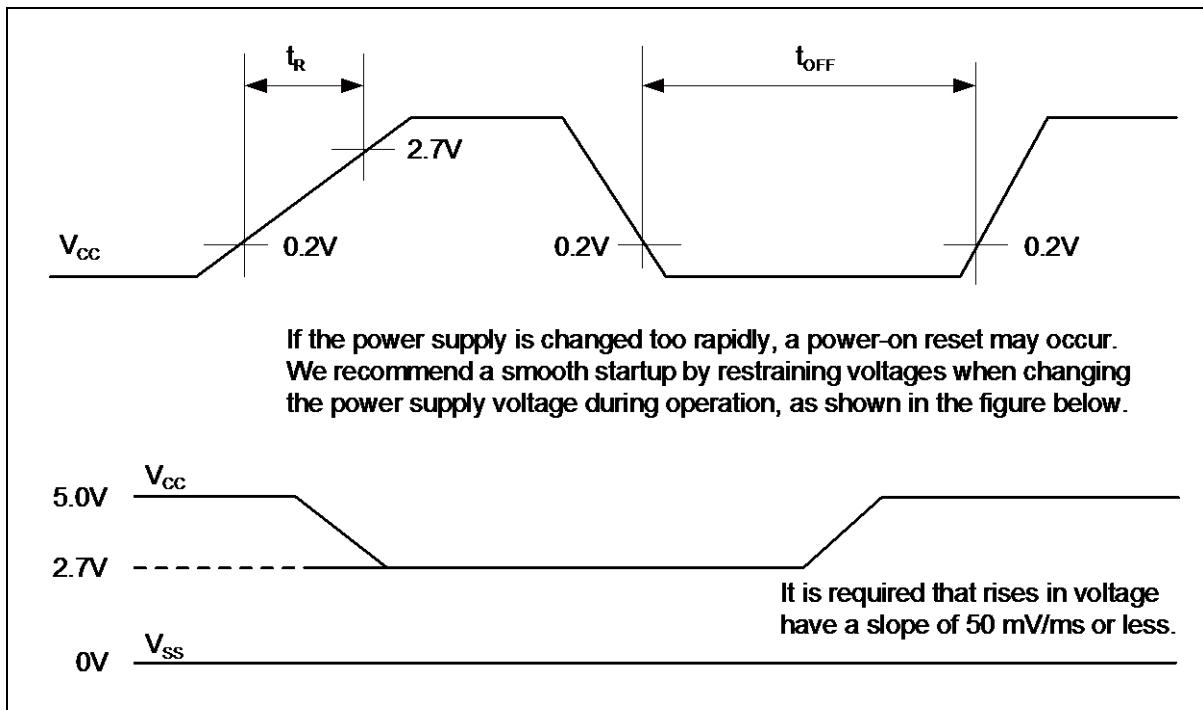
14.4.4 Internal Clock Timing
 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^\circ C \text{ to } +125^\circ C)$

Parameter	Symbol	Value		Unit
		Min	Max	
Internal System clock frequency (CLKS1 and CLKS2)	f_{CLKS1}, f_{CLKS2}	-	54	MHz
Internal CPU clock frequency (CLKB), Internal peripheral clock frequency (CLKP1)	f_{CLKB}, f_{CLKP1}	-	32	MHz
Internal peripheral clock frequency (CLKP2)	f_{CLKP2}	-	32	MHz

14.4.7 Power-on Reset Timing

($V_{CC} = AV_{CC} = 2.7V$ to $5.5V$, $V_{SS} = AV_{SS} = 0V$, $T_A = -40^{\circ}C$ to $+125^{\circ}C$)

Parameter	Symbol	Pin name	Value			Unit
			Min	Typ	Max	
Power on rise time	t_R	Vcc	0.05	-	30	ms
Power off time	t_{OFF}	Vcc	1	-	-	ms



14.4.8 USART Timing

($V_{CC} = AV_{CC} = 2.7V$ to $5.5V$, $V_{SS} = AV_{SS} = 0V$, $T_A = -40^\circ C$ to $+125^\circ C$, $C_L=50pF$)

Parameter	Symbol	Pin name	Conditions	$4.5V \leq V_{CC} < 5.5V$		$2.7V \leq V_{CC} < 4.5V$		Unit
				Min	Max	Min	Max	
Serial clock cycle time	t_{SCYC}	SCKn	Internal shift clock mode	$4t_{CLKP1}$	-	$4t_{CLKP1}$	-	ns
SCK \downarrow \rightarrow SOT delay time	t_{SLOVI}	SCKn, SOTn		- 20	+ 20	- 30	+ 30	ns
SOT \rightarrow SCK \uparrow delay time	t_{OVSHI}	SCKn, SOTn		$N \times t_{CLKP1} - 20$	-	$N \times t_{CLKP1} - 30$	-	ns
SIN \rightarrow SCK \uparrow setup time	t_{IVSHI}	SCKn, SINn		$t_{CLKP1} + 45$	-	$t_{CLKP1} + 55$	-	ns
SCK \uparrow \rightarrow SIN hold time	t_{SHIXI}	SCKn, SINn		0	-	0	-	ns
Serial clock "L" pulse width	t_{SLSH}	SCKn	External shift clock mode	$t_{CLKP1} + 10$	-	$t_{CLKP1} + 10$	-	ns
Serial clock "H" pulse width	t_{SHSL}	SCKn		$t_{CLKP1} + 10$	-	$t_{CLKP1} + 10$	-	ns
SCK \downarrow \rightarrow SOT delay time	t_{SLOVE}	SCKn, SOTn		-	$2t_{CLKP1} + 45$	-	$2t_{CLKP1} + 55$	ns
SIN \rightarrow SCK \uparrow setup time	t_{IVSHE}	SCKn, SINn		$t_{CLKP1}/2 + 10$	-	$t_{CLKP1}/2 + 10$	-	ns
SCK \uparrow \rightarrow SIN hold time	t_{SHIXE}	SCKn, SINn		$t_{CLKP1} + 10$	-	$t_{CLKP1} + 10$	-	ns
SCK fall time	t_F	SCKn		-	20	-	20	ns
SCK rise time	t_R	SCKn		-	20	-	20	ns

Notes:

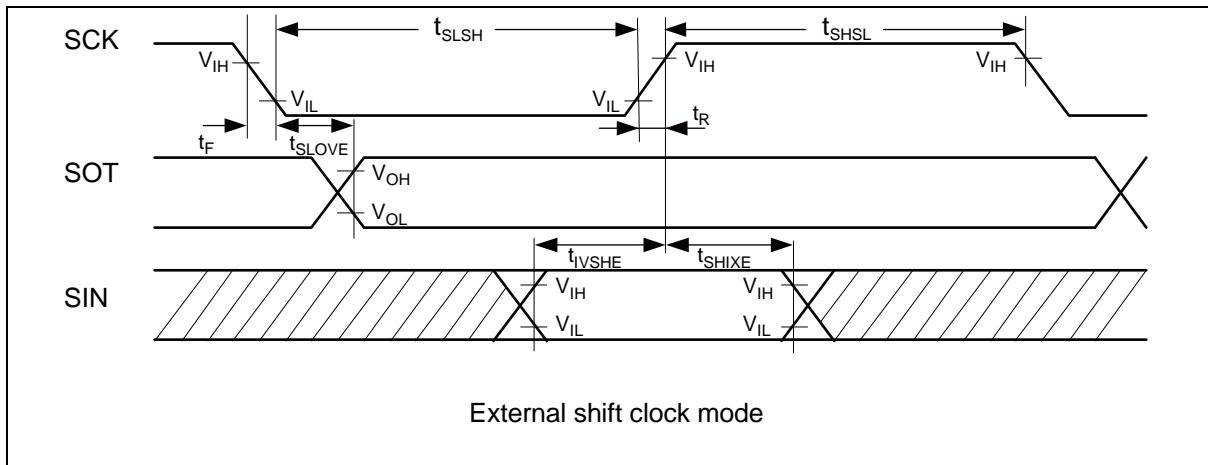
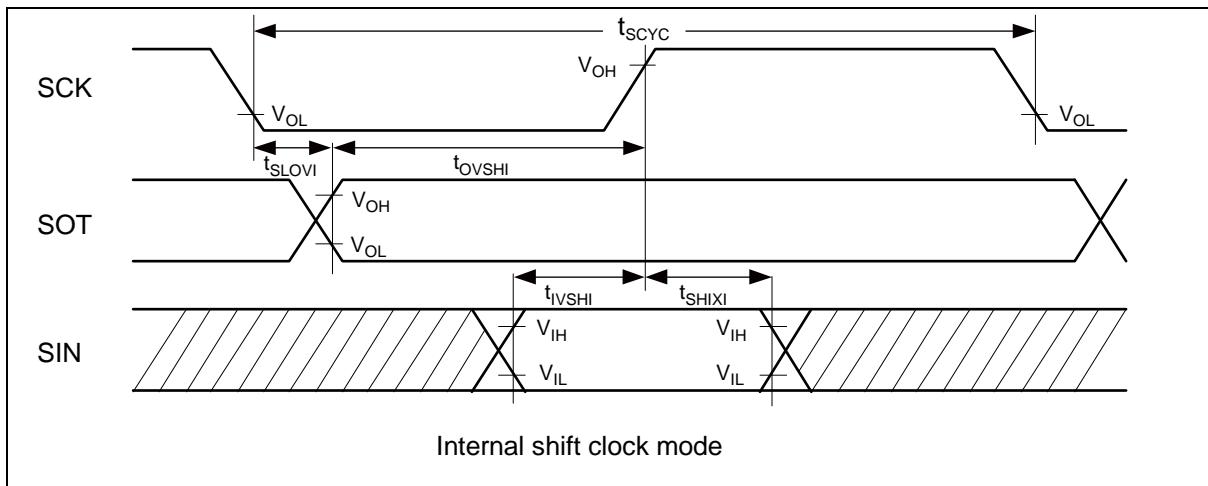
- AC characteristic in CLK synchronized mode.
- C_L is the load capacity value of pins when testing.
- Depending on the used machine clock frequency, the maximum possible baud rate can be limited by some parameters. These parameters are shown in "MB96600 series HARDWARE MANUAL".
- t_{CLKP1} indicates the peripheral clock 1 (CLKP1), Unit: ns
- These characteristics only guarantee the same relocate port number.
For example, the combination of SCKn and SOTn_R is not guaranteed.

*: Parameter N depends on t_{SCYC} and can be calculated as follows:

- If $t_{SCYC} = 2 \times k \times t_{CLKP1}$, then $N = k$, where k is an integer > 2
- If $t_{SCYC} = (2 \times k + 1) \times t_{CLKP1}$, then $N = k + 1$, where k is an integer > 1

Examples:

t_{SCYC}	N
$4 \times t_{CLKP1}$	2
$5 \times t_{CLKP1}, 6 \times t_{CLKP1}$	3
$7 \times t_{CLKP1}, 8 \times t_{CLKP1}$	4
...	...



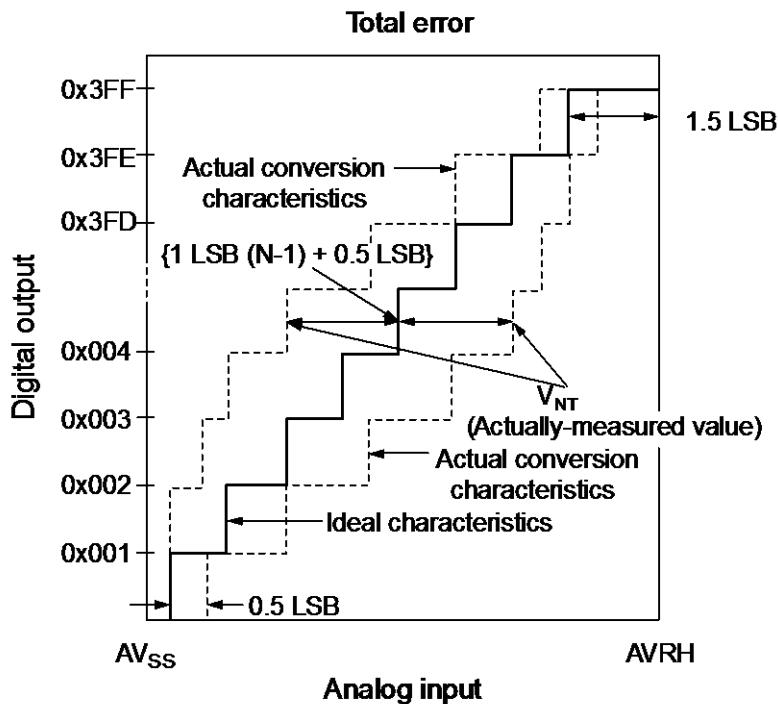
14.5 A/D Converter

14.5.1 Electrical Characteristics for the A/D Converter

($V_{CC} = AV_{CC} = 2.7V$ to $5.5V$, $V_{SS} = AV_{SS} = 0V$, $T_A = -40^\circ C$ to $+125^\circ C$)

Parameter	Symbol	Pin name	Value			Unit	Remarks
			Min	Typ	Max		
Resolution	-	-	-	-	10	bit	
Total error	-	-	-3.0	-	+3.0	LSB	
Nonlinearity error	-	-	-2.5	-	+2.5	LSB	
Differential Nonlinearity error	-	-	-1.9	-	+1.9	LSB	
Zero transition voltage	V_{OT}	ANn	Typ - 20	$AV_{SS} + 0.5LSB$	Typ + 20	mV	
Full scale transition voltage	V_{FST}	ANn	Typ - 20	$AV_{RH} - 1.5LSB$	Typ + 20	mV	
Compare time *	-	-	1.0	-	5.0	μs	$4.5V \leq AV_{CC} \leq 5.5V$
			2.2	-	8.0	μs	$2.7V \leq AV_{CC} < 4.5V$
Sampling time *	-	-	0.5	-	-	μs	$4.5V \leq AV_{CC} \leq 5.5V$
			1.2	-	-	μs	$2.7V \leq AV_{CC} < 4.5V$
Power supply current	I_A	AV_{CC}	-	2.0	3.1	mA	A/D Converter active
	I_{AH}		-	-	3.3	μA	A/D Converter not operated
Reference power supply current (between AV_{RH} and AV_{SS})	I_R	AV_{RH}	-	520	810	μA	A/D Converter active
	I_{RH}		-	-	1.0	μA	A/D Converter not operated
Analog input capacity	C_{VIN}	AN8, 9, 12, 13	-	-	15.5	pF	Normal outputs
		AN16 to 23	-	-	17.4	pF	High current outputs
Analog impedance	R_{VIN}	ANn	-	-	1450	Ω	$4.5V \leq AV_{CC} \leq 5.5V$
			-	-	2700	Ω	$2.7V \leq AV_{CC} < 4.5V$
Analog port input current (during conversion)	I_{AIN}	AN8, 9, 12, 13	-1.0	-	+1.0	μA	$AV_{SS} < V_{AIN} < AV_{CC}, AVRH$
		AN16 to 23	-3.0	-	+3.0	μA	
Analog input voltage	V_{AIN}	ANn	AV_{SS}	-	AV_{RH}	V	
Reference voltage range	-	AVRH	$AV_{CC} - 0.1$	-	AV_{CC}	V	
Variation between channels	-	ANn	-	-	4.0	LSB	

*: Time for each channel.



$$1\text{LSB} (\text{Ideal value}) = \frac{AV_{RH} - AV_{SS}}{1024} [\text{V}]$$

$$\text{Total error of digital output } N = \frac{V_{NT} - \{1\text{LSB} \times (N - 1) + 0.5\text{LSB}\}}{1\text{LSB}}$$

N : A/D converter digital output value.

V_{NT} : Voltage at which the digital output changes from $0x(N + 1)$ to $0xN$.

V_{OT} (Ideal value) = $AV_{SS} + 0.5\text{LSB}$ [V]

V_{FST} (Ideal value) = $AV_{RH} - 1.5\text{LSB}$ [V]

14.6 Low Voltage Detection Function Characteristics

($V_{CC} = AV_{CC} = 2.7V$ to $5.5V$, $V_{SS} = AV_{SS} = 0V$, $T_A = -40^\circ C$ to $+125^\circ C$)

Parameter	Symbol	Conditions	Value			Unit
			Min	Typ	Max	
Detected voltage ^{*1}	V_{DL0}	CILCR:LVL = 0000 _B	2.70	2.90	3.10	V
	V_{DL1}	CILCR:LVL = 0001 _B	2.79	3.00	3.21	V
	V_{DL2}	CILCR:LVL = 0010 _B	2.98	3.20	3.42	V
	V_{DL3}	CILCR:LVL = 0011 _B	3.26	3.50	3.74	V
	V_{DL4}	CILCR:LVL = 0100 _B	3.45	3.70	3.95	V
	V_{DL5}	CILCR:LVL = 0111 _B	3.73	4.00	4.27	V
	V_{DL6}	CILCR:LVL = 1001 _B	3.91	4.20	4.49	V
Power supply voltage change rate ^{*2}	dV/dt	-	- 0.004	-	+ 0.004	V/ μ s
Hysteresis width	V_{HYS}	CILCR:LVHYS=0	-	-	50	mV
		CILCR:LVHYS=1	80	100	120	mV
Stabilization time	$T_{LVDSTAB}$	-	-	-	75	μ s
Detection delay time	t_d	-	-	-	30	μ s

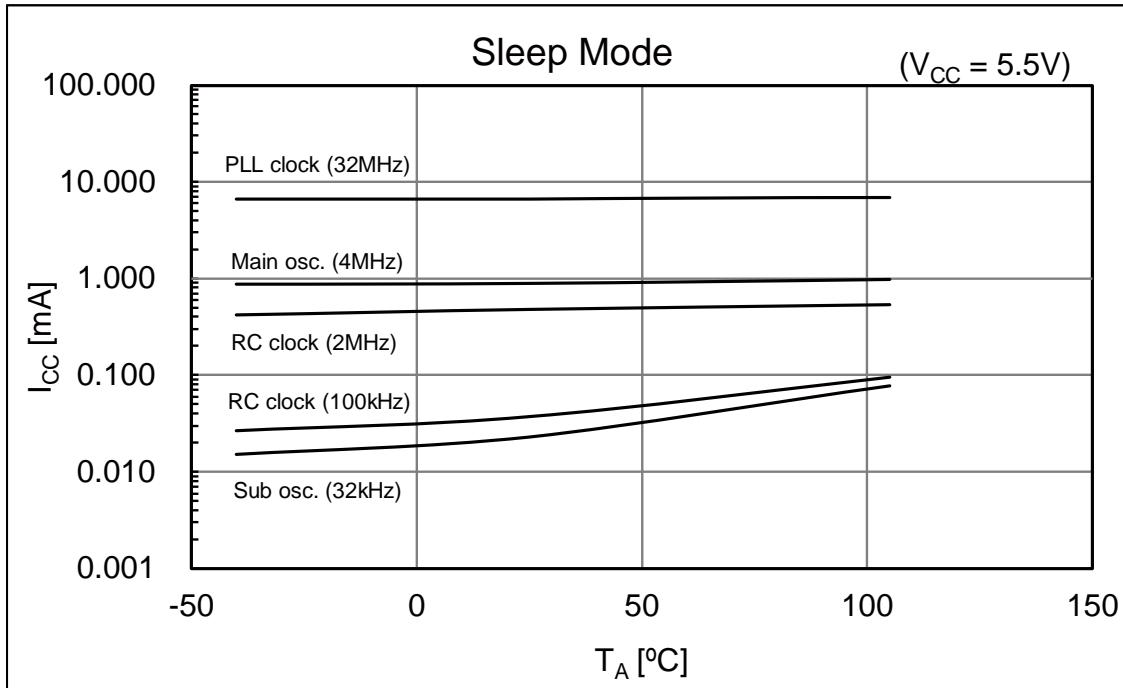
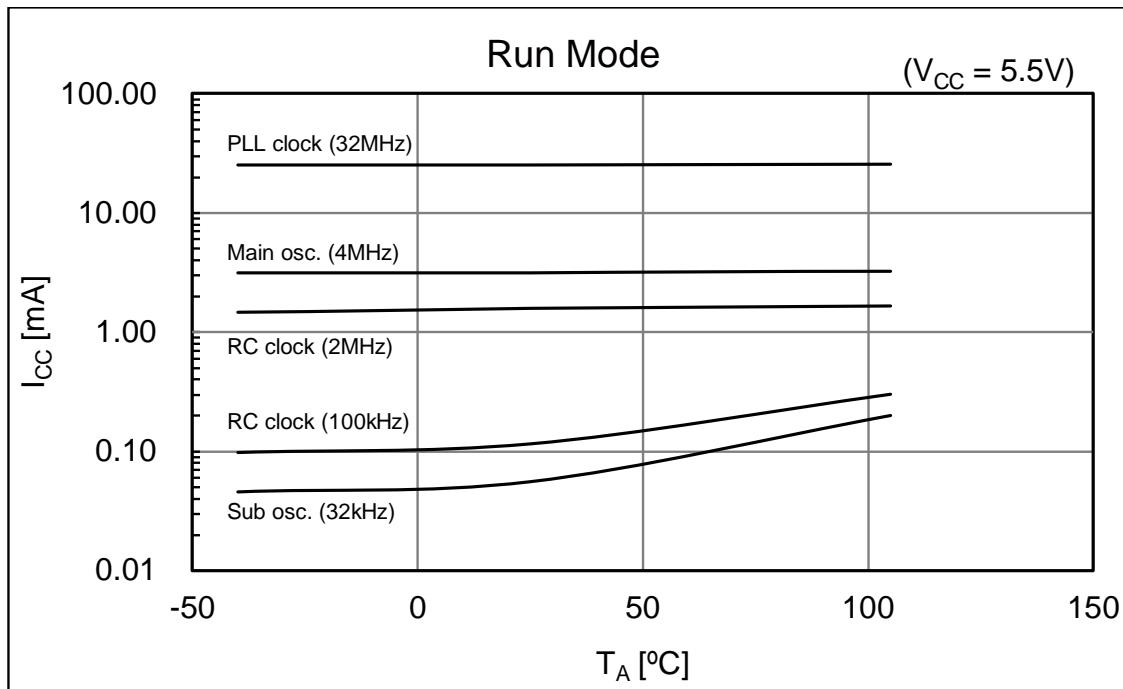
^{*1}: If the power supply voltage fluctuates within the time less than the detection delay time (t_d), there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

^{*2}: In order to perform the low voltage detection at the detection voltage (V_{DLX}), be sure to suppress fluctuation of the power supply voltage within the limits of the change ration of power supply voltage.

15. Example Characteristics

This characteristic is an actual value of the arbitrary sample. It is not the guaranteed value.

■MB96F625



■ Used setting

Mode	Selected Source Clock	Clock/Regulator and FLASH Settings
Run mode	PLL	CLKS1 = CLKS2 = CLKB = CLKPI = CLKP2 = 32MHz
	Main osc.	CLKS1 = CLKS2 = CLKB = CLKPI = CLKP2 = 4MHz
	RC clock fast	CLKS1 = CLKS2 = CLKB = CLKPI = CLKP2 = 2MHz
	RC clock slow	CLKS1 = CLKS2 = CLKB = CLKPI = CLKP2 = 100kHz
	Sub osc.	CLKS1 = CLKS2 = CLKB = CLKPI = CLKP2 = 32kHz
Sleep mode	PLL	CLKS1 = CLKS2 = CLKPI = CLKP2 = 32MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	Main osc.	CLKS1 = CLKS2 = CLKPI = CLKP2 = 4MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock fast	CLKS1 = CLKS2 = CLKPI = CLKP2 = 2MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock slow	CLKS1 = CLKS2 = CLKPI = CLKP2 = 100kHz Regulator in Low Power Mode, (CLKB is stopped in this mode)
	Sub osc.	CLKS1 = CLKS2 = CLKPI = CLKP2 = 32kHz Regulator in Low Power Mode, (CLKB is stopped in this mode)
Timer mode	PLL	CLKMC = 4MHz, CLKPLL = 32MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	Main osc.	CLKMC = 4MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock fast	CLKMC = 2MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock slow	CLKMC = 100kHz (System clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode
	Sub osc.	CLKMC = 32 kHz (System clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode
Stop mode	stopped	(All clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode